

Application Data Sheet

Application Information

Application Type::	Regular
Subject Matter::	Utility
Suggested Group Art Unit::	Not Yet Assigned
CD-ROM or CD-R?::	None
Sequence submission?::	None
Computer Readable Form (CRF)?::	No
Title::	NONVOLATILE SEMICONDUCTOR STORAGE DEVICE AND ROW-LINE SHORT DEFECT DETECTION METHOD
Attorney Docket Number::	559502000200
Request for Early Publication?::	No
Request for Non-Publication?::	No
Total Drawing Sheets::	4
Small Entity?::	No
Petition included?::	No
Secrecy Order in Parent Appl.?::	No

Applicant Information

Applicant Authority Type::	Inventor
Primary Citizenship Country::	Japan
Status::	Full Capacity
Given Name::	Shoichi
Family Name::	TANNO
City of Residence::	Kashiba
Country of Residence::	Japan
Street of mailing address::	Suite #208, 9-5 Mamigaoka 6-chome
City of mailing address::	Kashiba
State or Province of mailing address::	Nara
Country of mailing address::	Japan

Postal or Zip Code of mailing address:: 639-0223

Correspondence Information

Correspondence Customer Number:: 25226

Representative Information

Representative Customer Number:: 25226

Foreign Priority Information

Country::	Application number::	FilingDate::	Priority Claimed::
Japan	2002-345214	11/28/02	Yes

Assignee Information

Assignee name:: SHARP KABUSHIKI KAISHA
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